

# Advances in VNA-based Signal Integrity Tools and Techniques

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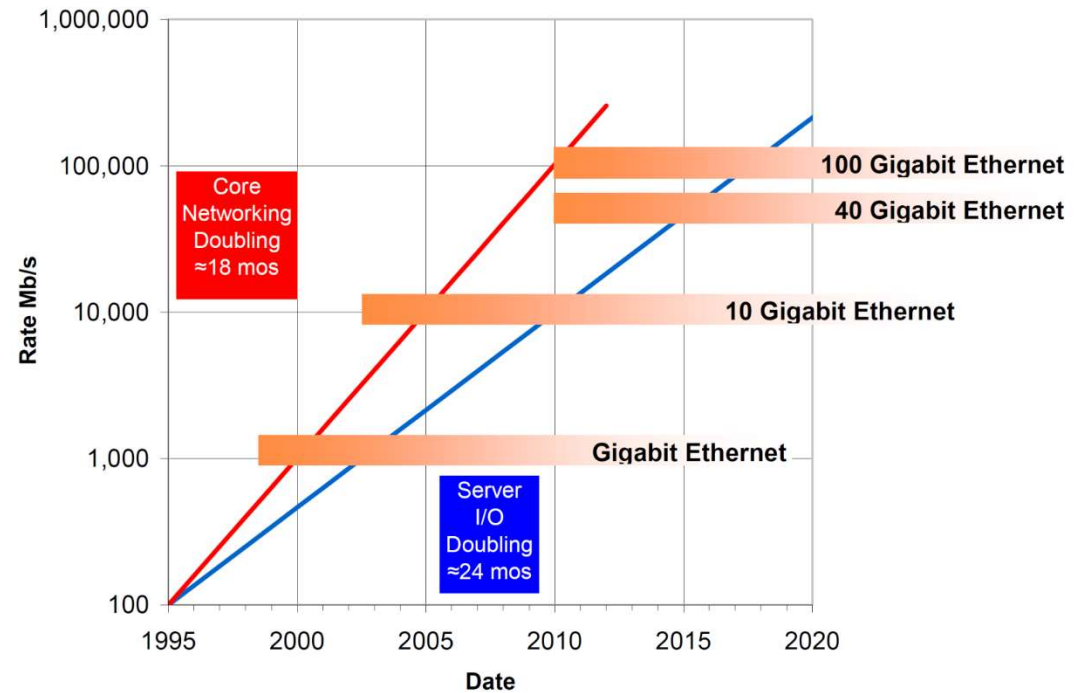
# Outline

- Technology Driver: Data Rates
- Improving measurement technology for SI applications
  - De-embedding methods
  - De-embedding tools



# Data Rate Trajectory

- LTE success driving wired communicating networks
- Amount of data generated has exploded
- Core network capacity doubles every 18 months
- Server I/O doubles every 24 months
- 100 GE is currently deployed



# Double Data Rate with PAM4

PAM4 example

- 4 discrete levels (symbols)
- 2 bits per symbol

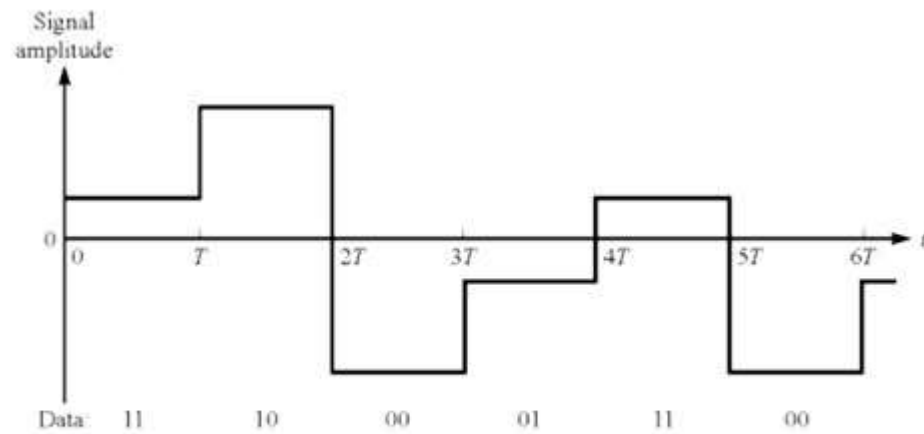


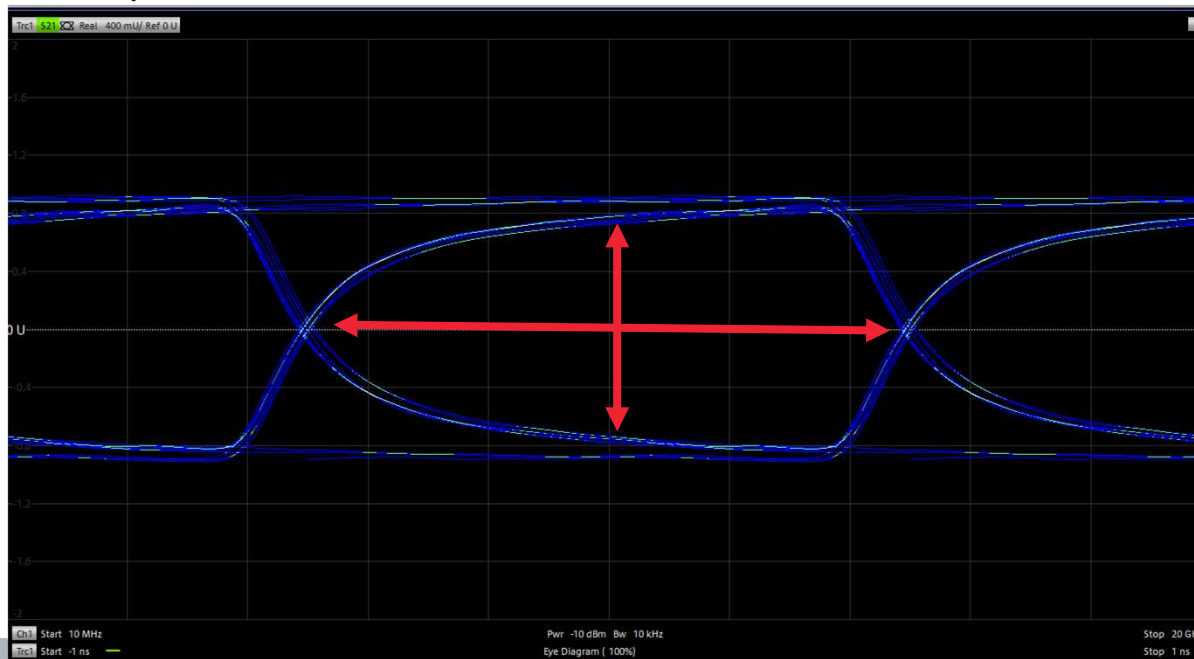
Fig.1 A PAM-4 signal in time domain,  $T$  = symbol period.



# What is an Eye Diagram?

- Overlay of a bit sequence of a digital signal
- Look at 21-bit sequence "010101101001110010111"

Bit 1  
Bit 2  
Bit 3  
Bit 4  
Bit 7  
Bit 21

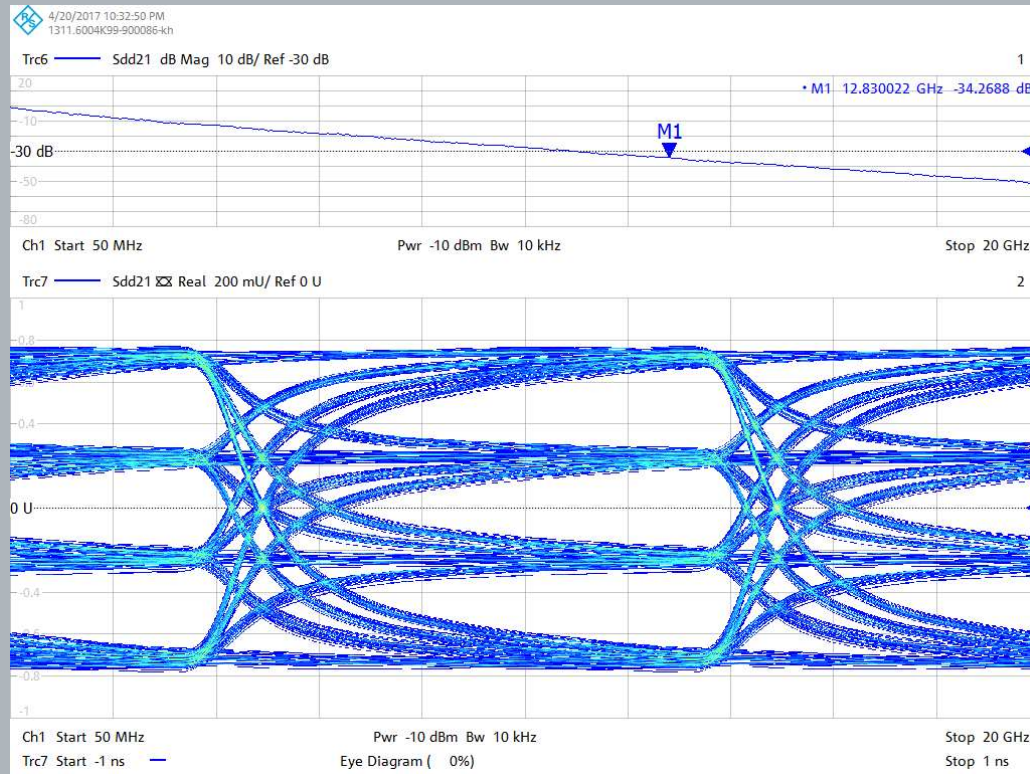


Eye Height

Eye Width



# PAM4 Measurement



## Comparison of PAM4 vs. NRZ

### ■ Advantages:

- Requires ½ bandwidth of NRZ

### ■ Challenges:

- 1/3 eye height of NRZ
- ½ to 1/3 eye width of NRZ
- Eye levels are asymmetric
- More sensitive to ISI than NRZ
- More sensitive to reflection than NRZ
- More sensitive to crosstalk than NRZ
- Much more sensitive to intra-pair skew than NRZ
- More sensitive to nonlinearities than NRZ

**Accurate Channel characterization is crucial for PAM4 signaling**



# Improving measurement technology for SI applications

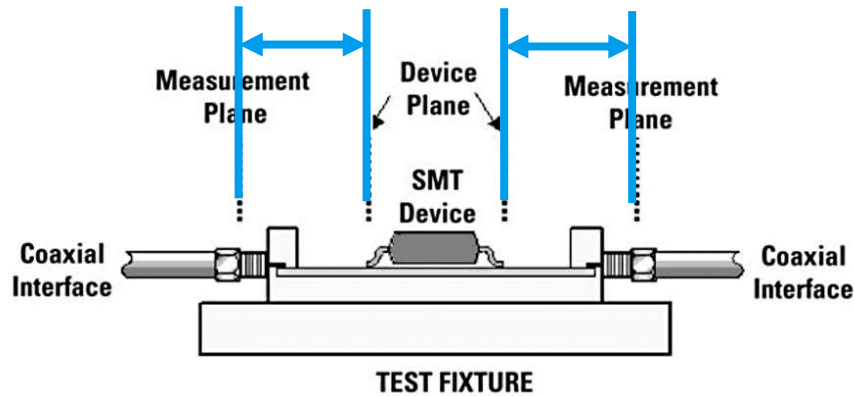
- SI Measurement Objective is similar to ANY VNA Measurement Objective:
  - Measure ONLY the DUT
    - Remove reflections
    - Remove extraneous loss
    - Remove extraneous phase shift/rotations
  - Focus on Ease of Use...



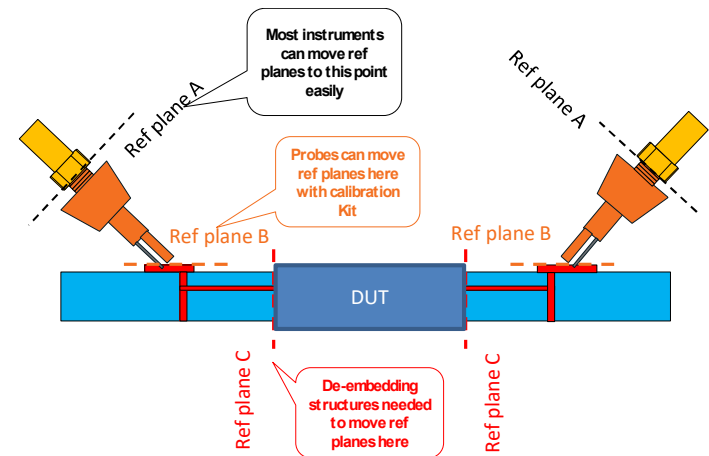


# Problem Description: Device Performance

How do you measure this?



- Is the left side = right side?
  - Different length
  - Skew (glass weave skew)?
  - Manufacturing tolerances?
- Is the material the same over the whole PCB
  - Glass/fiber weave effect



# Concept of test coupon

- Add test coupon to characterize trace
  - Either on the same board
  - External board but same material
  - External board and different material
- Typical calibration standards
  - TRL calibration standards
  - 2x through
  - 1x through
  - Other reference traces
- Advanced de-embedding methods
  - Can handle coupon with (slightly) different material

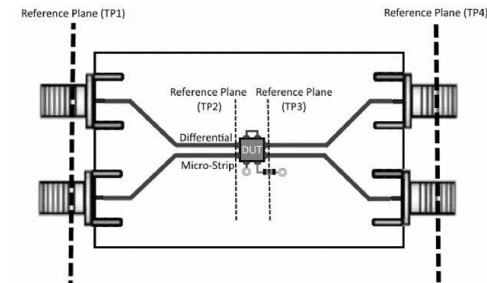
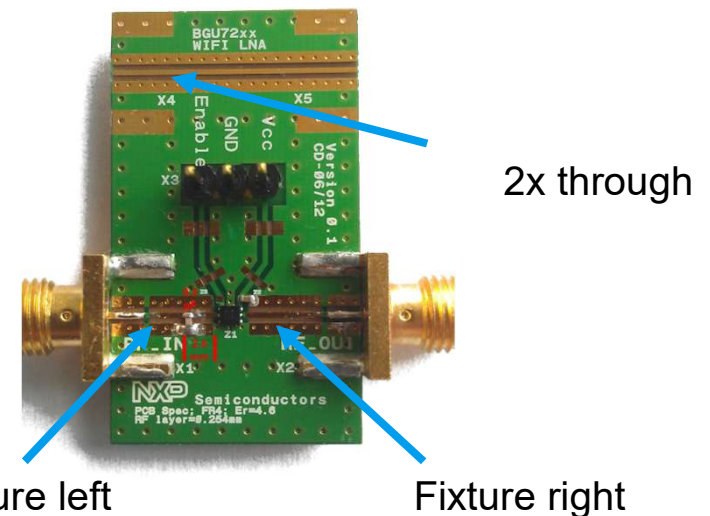


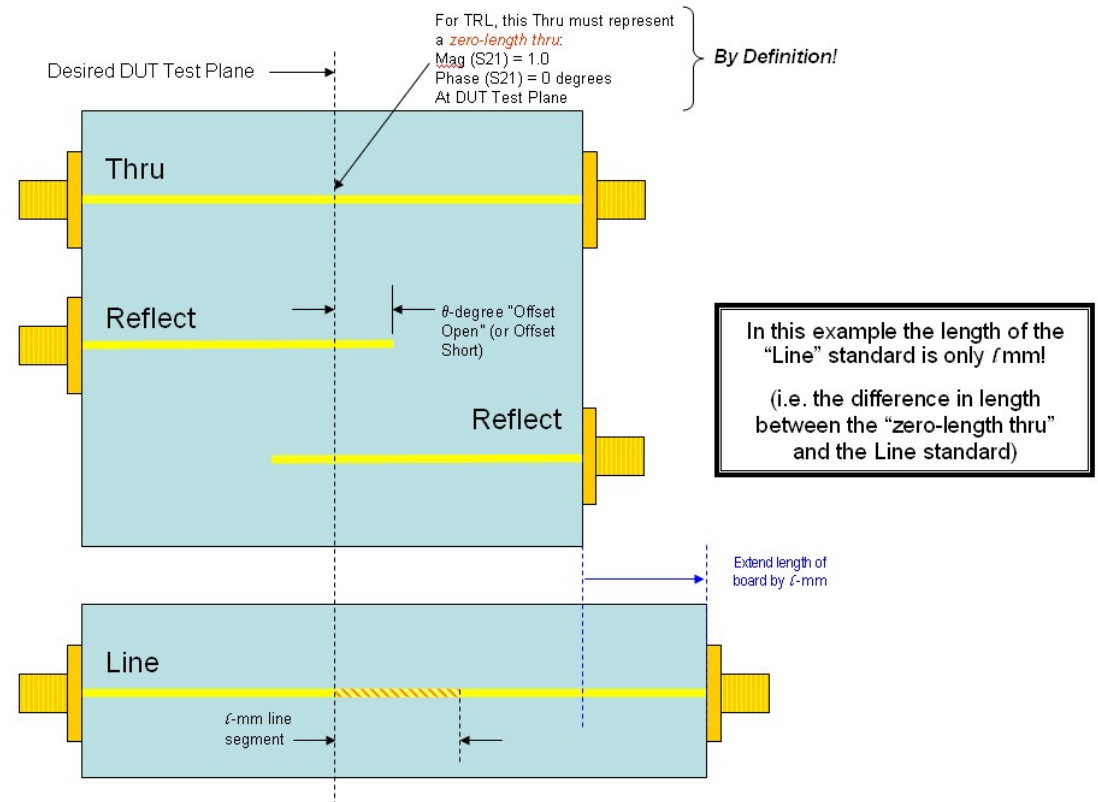
Figure GG-GG — Coaxial connectors on a PCB with differential micro-strip traces to a DUT



# Classic approach

## TRL Calibration

- Requires:
  - Reflect standard
  - Zero-length through standard
  - Line Standard:
    - 20 degrees at lowest freq
    - 160 degrees at highest freq



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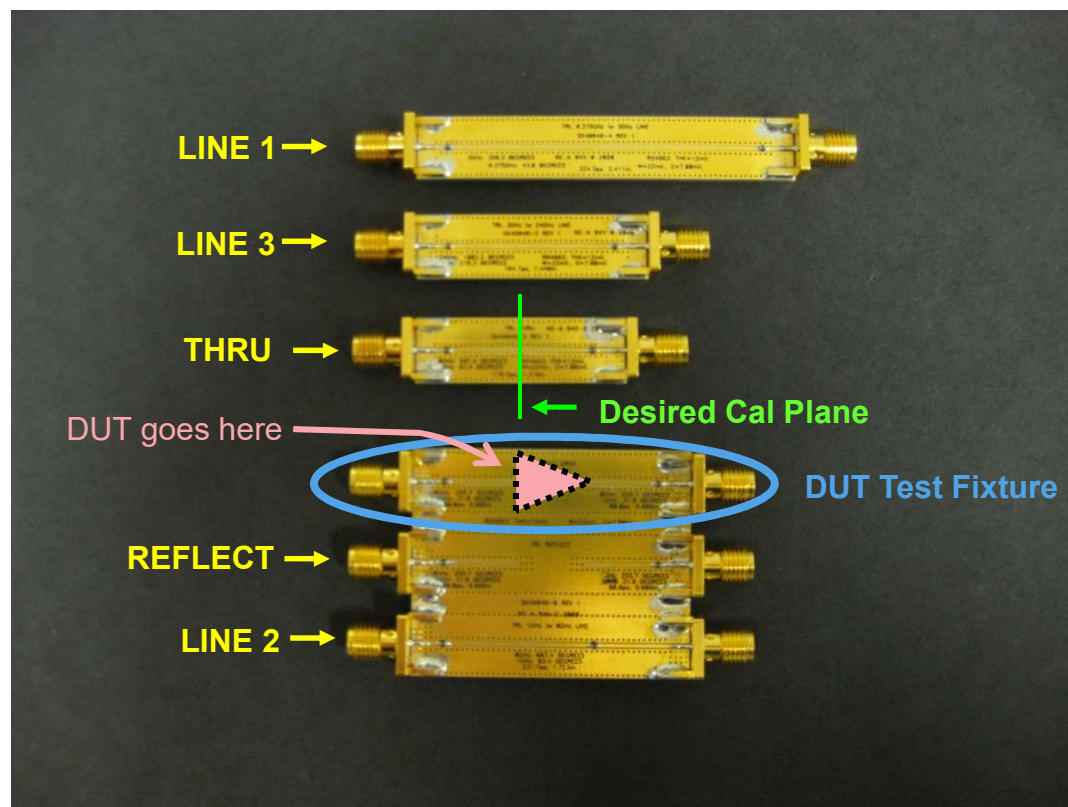
May 11, 2007



## TRL Standards for Custom Kit (Three Line standards cover 375 MHz to 24 GHz)

### TRL Challenges

- Multiple lines required to cover higher frequencies
- Still requires Match standard for lower frequencies
- Cal Plane established in center of THRU standard
- Cal Plane established in center of THRU standard

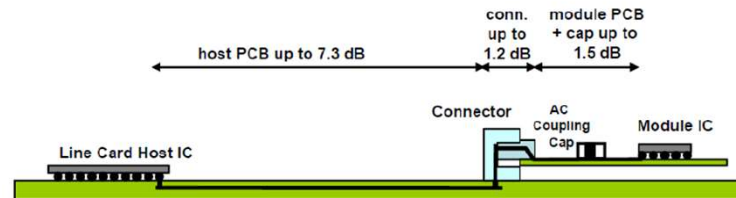


# CEI56, VSR, MR, LR

## Very Short Reach

- 10 cm
- Chip-to-Chip
- One Connector

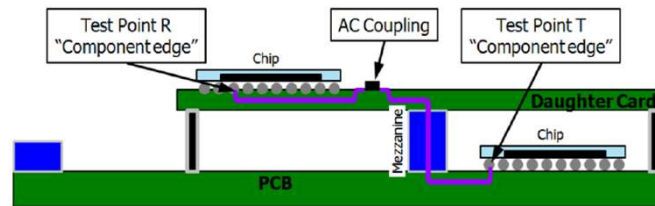
Figure 16-15. CEI-56G-VSR-PAM4 Channel Reference Model



## Medium Reach

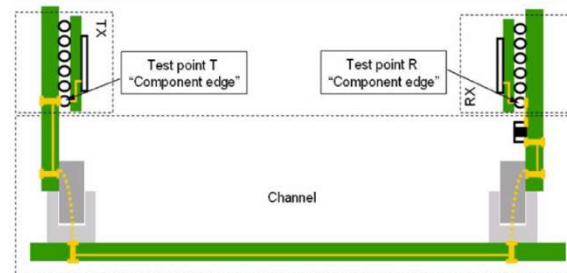
- 50 cm
- Chip-to-Chip
- One Connector

Figure 17-1. CEI-56G-MR Reference Model



## Long Reach

- Chip-to-Chip
- Two Connector



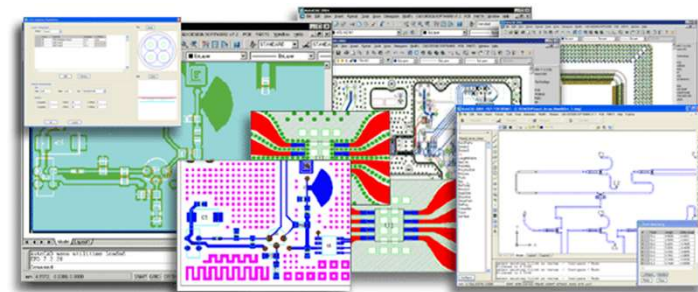
## Common Features:

- Equalization
  - CTLE/FFE/DFE
- Error correction
  - FEC



## Alternative (simpler) solutions

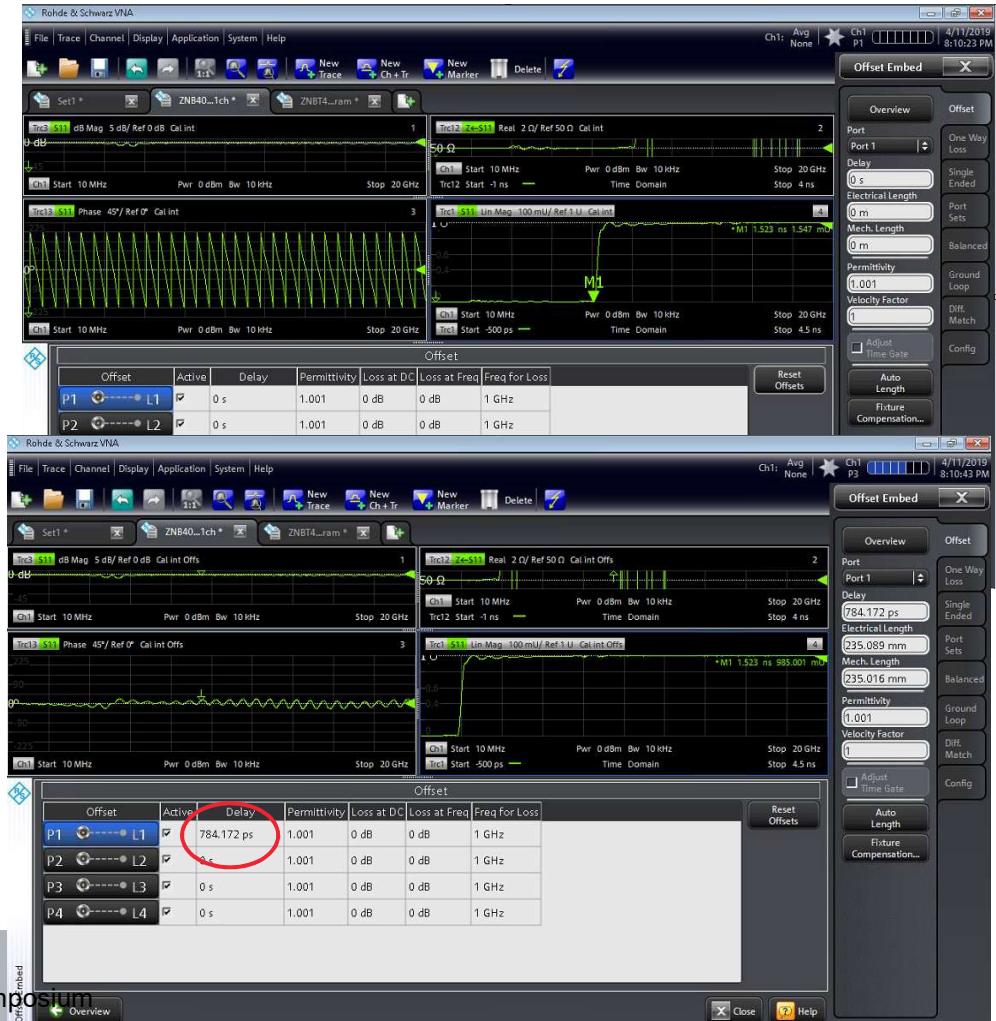
- Use Offset De-embed
- One Way Loss/Auto Length/Loss
- Use S-parameters from board simulation
- Use advanced fixture de-embedding techniques



# Alternative approaches

## Auto Length

- Advantages:
  - Simple (requires only an OPEN)
  - Remove reflections
  - Remove extraneous loss
  - Remove extraneous phase shift/rotations
- Disadvantages:
  - Assumes line (to be removed) is  $Z_0$

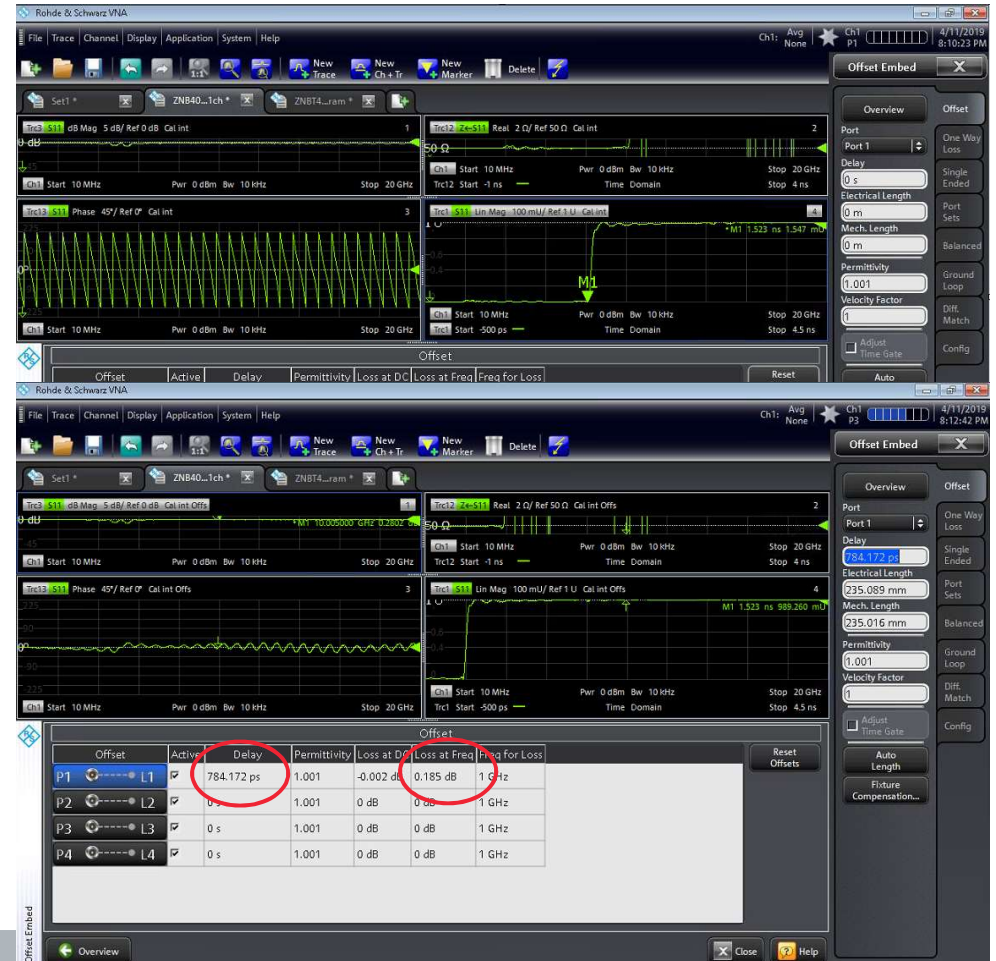




# Alternative approaches

## ■ Auto Length & Loss

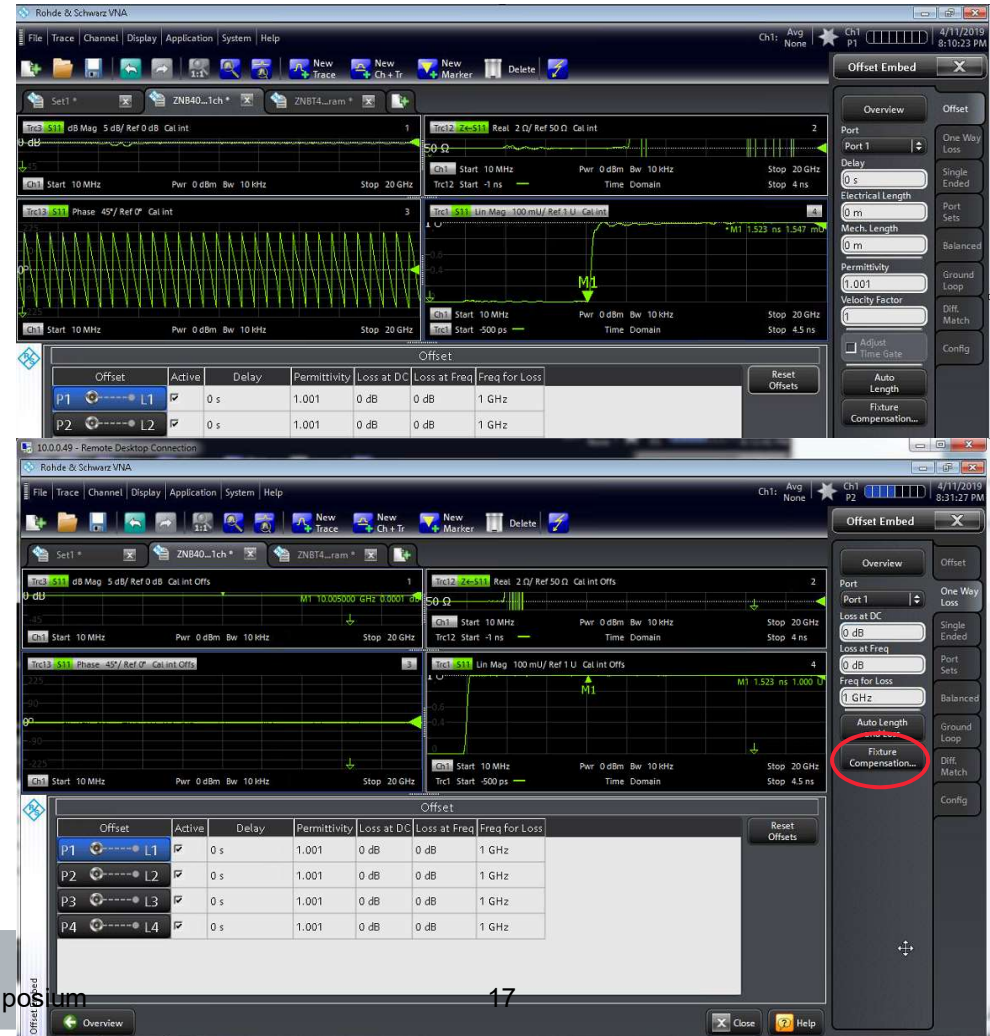
- Advantages:
  - Simple (requires only an OPEN)
  - Remove reflections
  - Remove extraneous loss
  - Remove extraneous phase shift/rotations
- Disadvantages:
  - Assumes line (to be removed) is  $Z_0$





# Alternative approaches

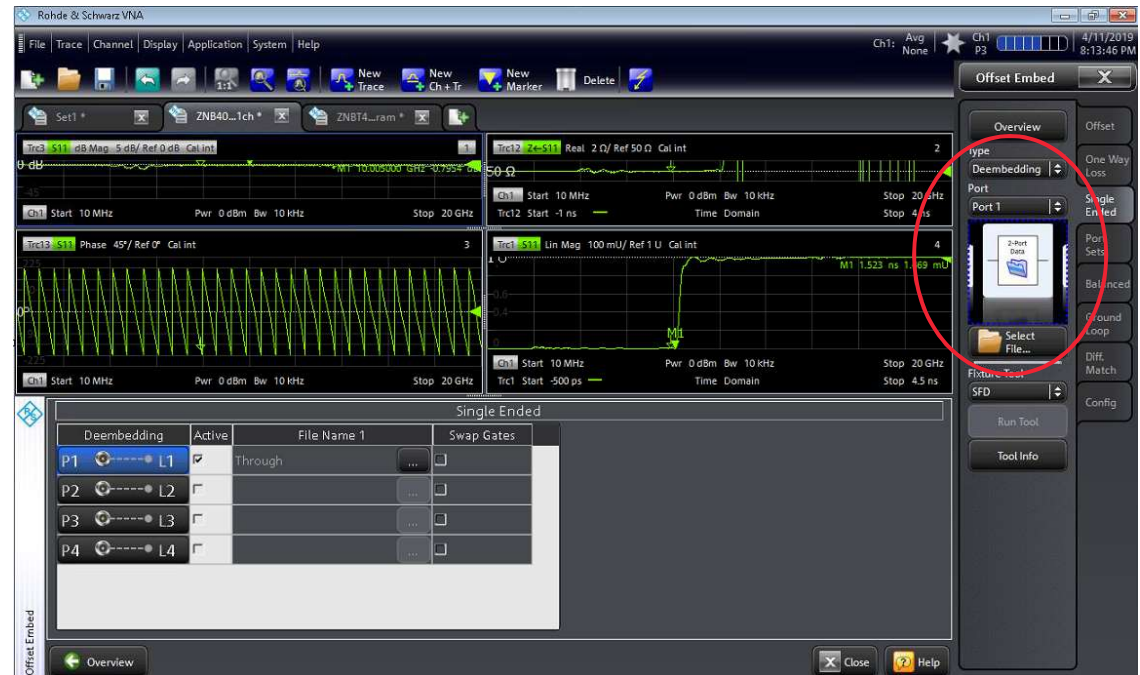
- Fixture Compensation
  - Advantages:
    - Simple (requires only an OPEN)
    - Remove reflections
    - Remove extraneous **loss**
    - Remove extraneous phase shift/rotations
  - Disadvantages:
    - Assumes line (to be removed) is  $Z_0$
    - Can provide “overly optimistic” results



# Alternative approaches

## ■ Fixture De-Embedding

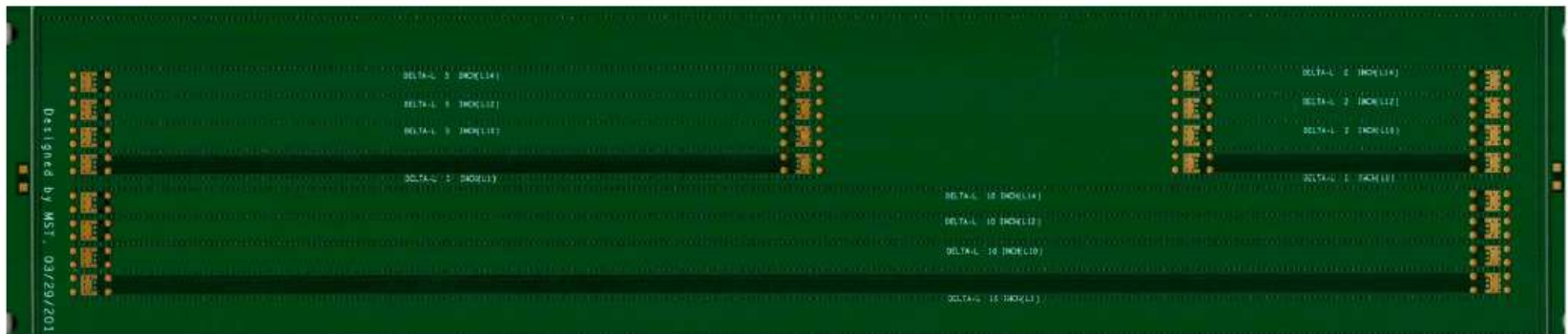
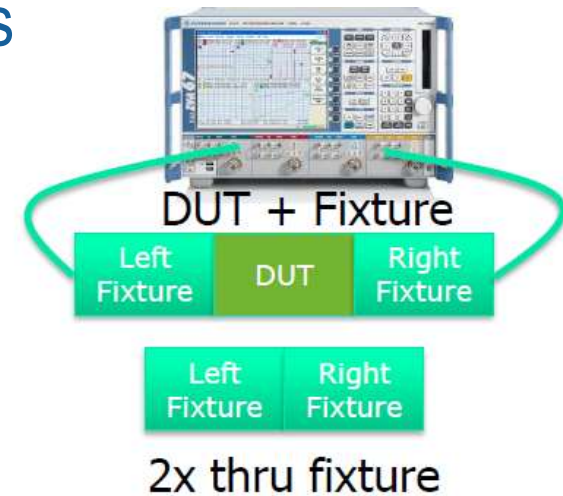
- Advantages:
  - Remove reflections
  - Remove extraneous loss
  - Remove extraneous phase shift/rotations
- Disadvantages:
  - Requires 2-port s-parameters
    - (measured or modelled)



# Advanced Fixture De-embedding Techniques

## 2-X Thru Tools:

- Keysight: AFR (Automatic Fixture Removal)
  - Packet Micro: SFD (Smart Fixture De-embedding)
  - Ataitec: ISD (In-Situ De-embedding)
- Disadvantages:
    - May produce non-casual response



# What is causality?

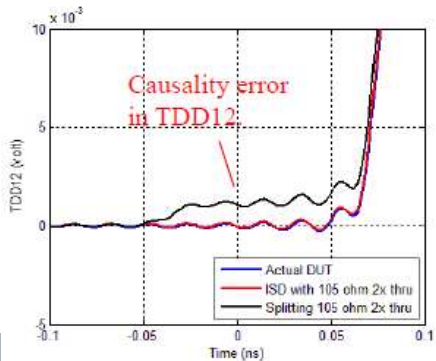
cau·sal·i·ty

noun

1. the relationship between cause and effect.
2. the principle that everything has a cause.

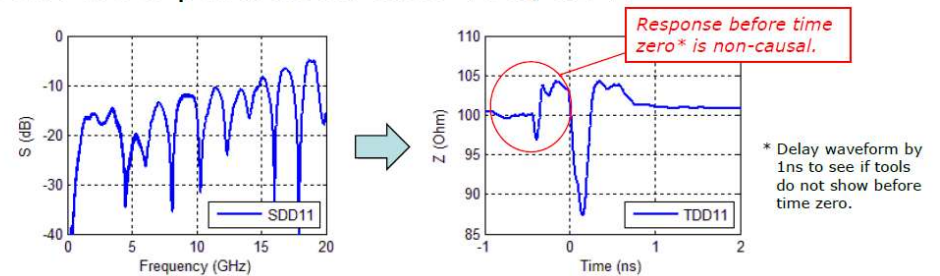
In other words:

Can not get something from nothing.

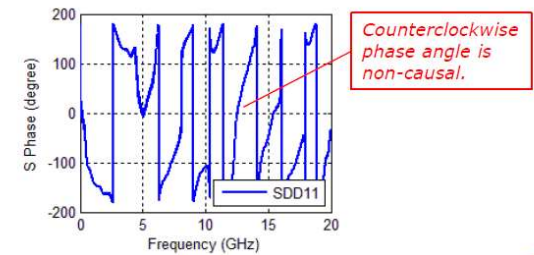


## How to identify non-causal S parameter

- Convert S parameter into TDR/TDT.



- Check phase angle.

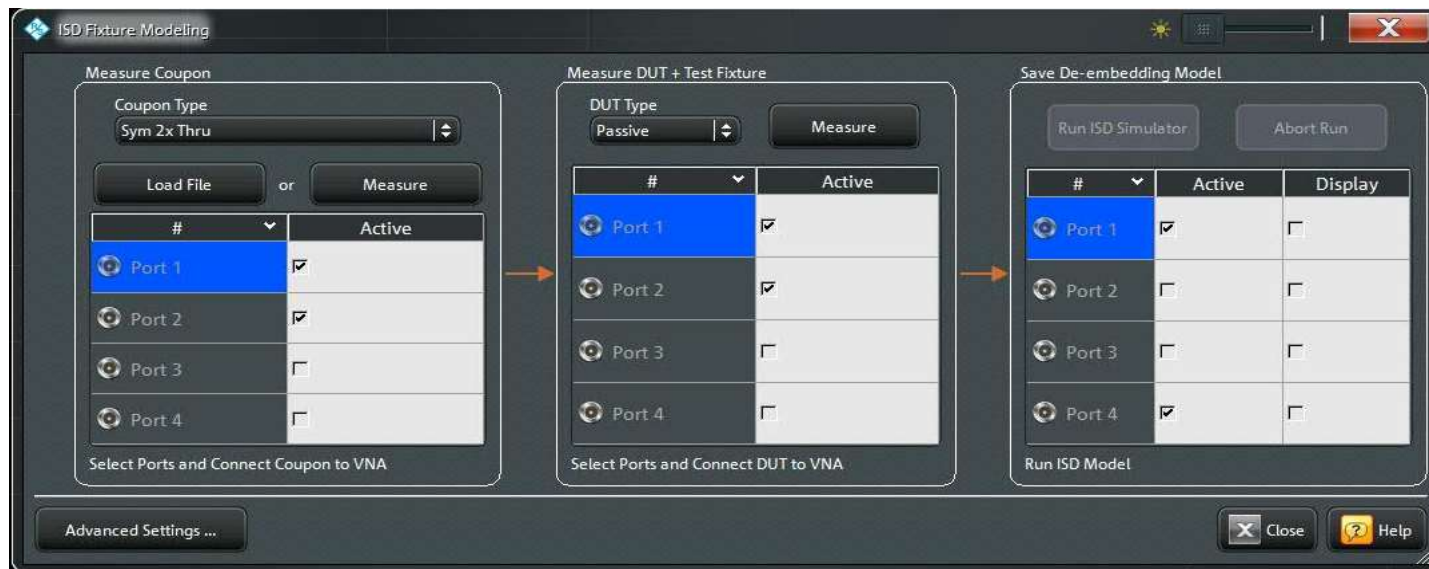


# ISD and SFD Dialog in ZNB, ZNBT Vector Network Analyzers

3 steps: 1) Measure Coupon

2) Measure DUT

3) Run De-embedding



ISD provided by Ataitec, SFD provided by PacketMicro

